
Contents

Foreword by Philippe Bogdanik	xi
Foreword by Gilles Zwingelstein	xiii
List of Notations	xv
List of Acronyms	xvii
Definitions	xix
Introduction	xxi
Part 1. Reliability	1
Chapter 1. Predictive Reliability	3
1.1. Concept of predictive reliability	3
1.2. FIDES methodology	4
1.2.1. Modeling reminder	4
1.2.2. Concept of life profile	5
1.3. Application example	7
1.3.1. Classical estimation	9
1.3.2. Estimation with a uniform law	10
1.3.3. Estimation with a normal distribution	11

1.4. Maintaining a reliability specification	11
1.5. Summary	12

Chapter 2. Statistical Characteristics of Exponential and Weibull Distributions. 13

2.1. Refresher about exponential and Weibull distributions	13
2.1.1. Exponential distribution	13
2.1.2. Weibull distribution	13
2.2. Parameter estimation for a reliability model using the maximum likelihood method	14
2.2.1. Full data	14
2.2.2. Type II right-censored data	15
2.3. Estimator properties	17
2.3.1. Notion of bias	17
2.3.2. Notion of coefficient of variation CV	19
2.4. Simulation of failure times by inverting the probability of failure	19
2.4.1. Generating failure times for the exponential distribution	19
2.4.2. Generating failure times for the Weibull distribution	20
2.5. Impact of temperature	21
2.6. Relative bias and coefficient of variation of the Weibull parameters	22
2.6.1. Relative bias of β	22
2.6.2. Relative bias of the parameter η	24
2.6.3. Coefficient of variation of the parameter β	24
2.6.4. Coefficient of variation of the parameter η	25
2.7. Simulation scenarios considered from the different parameters	26
2.7.1. Relative bias of β	26
2.7.2. Bias of Ea	27
2.7.3. Bias of C	28
2.7.4. Coefficient of variation of β	29
2.7.5. Coefficient of variation with Ea	30
2.7.6. Coefficient of variation with C	31
2.8. Summary	31

Chapter 3. System Reliability 33

3.1. Assumptions	34
3.2. Maintenance-free systems	34
3.2.1. Concept of the default rate	34
3.2.2. Maintenance-free serial system	37

3.2.3. Maintenance-free parallel system	39
3.2.4. Maintenance-free “k-out-of-n” redundancy	43
3.3. Maintenance-free systems	45
3.3.1. Concept of failure intensity and occurrence rate of Rocof failures	46
3.3.2. Serial system with maintenance	48
3.3.3. Parallel system with maintenance	61
3.3.4. k-out-of-n redundancy system with maintenance	67
3.4. Series/parallel system	73
3.4.1. Maintenance-free serial/parallel system.	73
3.4.2. Maintenance-enabled series/parallel systems	74
3.4.3. System-level renewal	76
3.4.4. Summary	78
3.5. Parallel/serial system	78
3.5.1. Maintenance-free parallel/serial system.	79
3.5.2. Maintenance-enabled parallel/serial system	81
3.6. Use cases	86
3.6.1. Thermostatic energy conversion	86
3.6.2. Avionics computer	91
Chapter 4. Impact of Temperature on Reliability	97
4.1. Arrhenius law	97
4.2. Operational life profile	98
4.3. Sedyakin’s principle.	98
4.4. Consequences for reliability estimates	100
4.5. Taking the effect of maintenance into consideration.	107
4.6. Summary	114
Chapter 5. Aging Tests	115
5.1. Accelerated aging test.	117
5.1.1. Principle	117
5.1.2. Modeling.	117
5.2. Aging test design	118
5.2.1. Input data.	118
5.2.2. Adjustment parameters	119
5.2.3. Product constraints	119
5.2.4. Impact of the shape parameter β of the Weibull distribution	120
5.2.5. Choosing the minimal and maximal temperatures.	120
5.3. Sequential test at two constant temperatures	121

5.4. Constant-level parallel testing	124
5.5. Constant-level mixed testing.	125
5.6. Summary	125
 Chapter 6. Application of the Noncentral Beta Distribution	 127
6.1. Context	127
6.2. The “noncentral beta” probability distribution	129
6.3. Measurement modeling.	130
6.4. Rejection method	132
6.5. Confidence interval for noncentral beta distribution.	136
6.6. Rationale for the choice of the noncentral beta distribution	137
6.7. Summary	139
 Chapter 7. Statistical Characteristics of HPP and PLP Processes	 141
7.1. Reminders about Poisson processes	141
7.2. HPP homogeneous Poisson process	141
7.2.1. Parameter HPP bias	142
7.2.2. Coefficient of variation of the HPP parameter	143
7.3. PLP power process	143
7.3.1. Power process simulations	145
7.3.2. Relative bias of the parameter β	145
7.3.3. Relative bias of the parameter α	146
7.3.4. Coefficient of variation of the parameter β	147
7.3.5. Coefficient of variation of the parameter α	147
7.4. Summary	148
 Part 2. Maintainability	 151
 Chapter 8. Maintainability	 153
8.1. Average number of failures	153
8.2. Serial system	154
8.2.1. Element-level renewal	154
8.2.2. System-level renewal	157
8.3. Parallel system	159
8.4. k/n system.	162
8.5. Avionics system	164
8.6. Summary	165

Part 3. Availability	167
Chapter 9. System Availability	169
9.1. Assumptions	169
9.2. Uptime and repair time: exponential distributions	171
9.3. Exponential distribution uptime and constant repair time.	174
9.4. Exponential distribution uptime and uniform distribution repair time	176
9.5. Exponential distribution uptimes and normal distribution repair times	178
9.6. Uptimes exponential distribution and repair times Weibull distribution	182
9.7. Serial system	183
9.8. Parallel system	186
9.9. k-out-of-n redundancy	189
9.10. Series/parallel system	192
9.11. Parallel/serial system	193
9.12. Energy conversion	194
9.13. Summary	200
Part 4. Safety	203
Chapter 10. FMEA Concurrent Failure Mechanisms	205
10.1. Maintenance-free industrial applications.	209
10.1.1. Exponential distribution	210
10.1.2. Weibull distribution.	210
10.2. Industrial applications with maintenance.	211
10.2.1. Exponential distributions with parameter λ_i	212
10.2.2. Weibull distributions	213
10.3. Consideration of physical contributions	215
10.3.1. Exponential law with no maintenance	215
10.3.2. Weibull distribution with no maintenance	217
10.3.3. Exponential distribution with maintenance	219
10.4. Summary	219
Chapter 11. Feared Events (FTA)	221
11.1. Introduction	221

11.2. Regulatory aspects	222
11.2.1. CS25 framework	222
11.2.2. Problems found	223
11.2.3. Using an exponential distribution.	226
11.2.4. Using a normal distribution	227
11.3. Probability of the occurrence of a feared event	228
11.3.1. OR gate with element testing	229
11.3.2. OR gate without element testing	230
11.3.3. AND gate with element testing	231
11.3.4. AND gate without element testing	234
11.4. Practical application	235
11.5. Summary	239
 Appendices	 241
 References	 249
 Index	 251